



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application: Ann-Shyn Chiang

Serial No.: 10/764,091

Filed: January 23, 2004

Art Unit: 2872

Examiner:

Confirmation No: 8254

For: METHOD FOR IMPROVING THE DEPTH OF FIELD AND  
RESOLUTION OF MICROSCOPY

**PRELIMINARY AMENDMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

Prior to examination on the merits, please amend the application as follows:

Amendments to the Specification begin on Page 2 of this paper.

Remarks begin on Page 3 of this paper.